

MOSFET

OptiMOS™ Power-MOSFET, 40 V

Features

- Optimized for synchronous rectification
- 175°C rated
- Very low on-state resistance R_{DS(on)}
- 100% avalanche tested
- Superior thermal resistance
- N-channel, logic level
- Pb-free lead plating; RoHS compliant
 Halogen-free according to IEC61249-2-21
- Higher solder joint reliability due to enlarged source interconnection

Product validation

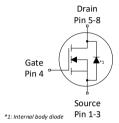
Fully qualified according to JEDEC for Industrial Applications

Table 1 **Key Performance Parameters**

Parameter	Value	Unit
V_{DS}	40	V
R _{DS(on),max}	1.4	mΩ
I_{D}	205	А
Qoss	54	nC
Qg(0V10V)	61	nC









Type/Ordering Code	Package	Marking	Related Links
BSC014N04LS	PG-TDSON-8	014N04LS	-

Public

OptiMOS™ Power-MOSFET, 40 V BSC014N04LS



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1 Maximum ratings

unless otherwise specified

Table 2 Maximum ratings

Davamatav	Symphol	,	Value	S	l lmit	Note/Test Condition	
Parameter	Symbol	Min. Typ.		Мах.	Unit	Note/ Test Condition	
Continuous drain current ¹⁾	I _D	205 145 176 124 33		А	$V_{\rm GS}$ =10 V, $T_{\rm C}$ =25 °C $V_{\rm GS}$ =10 V, $T_{\rm C}$ =100 °C $V_{\rm GS}$ =4.5 V, $T_{\rm C}$ =25 °C $V_{\rm GS}$ =4.5 V, $T_{\rm C}$ =100 °C $V_{\rm GS}$ =10 V, $T_{\rm A}$ =25 °C, $R_{\rm thJA}$ =50 K/W ²⁾		
Pulsed drain current ³⁾	I _{D,pulse}	-	-	820	А	<i>T</i> _c =25 °C	
Avalanche current, single pulse ⁴⁾	I _{AS}	-	-	50	А	<i>T</i> _C =25 °C	
Avalanche energy, single pulse	E _{AS}	-	-	170	mJ	$I_{\rm D}$ =50 A, $R_{\rm GS}$ =25 Ω	
Gate source voltage ⁵⁾	V_{GS}	-20	-	20	V	-	
Power dissipation P_{tot}		-	-	115 3.0	W	$T_{\rm C}$ =25 °C $T_{\rm A}$ =25 °C, $R_{\rm thJA}$ =50 K/W ²⁾	
Operating and storage temperature	$T_{\rm j},T_{\rm stg}$	-55	-	175	°C	-	

¹⁾ Rating refers to the product only with datasheet specified absolute maximum values, maintaining case temperature at 25°C. For higher case temperature please refer to Diagram 2. De-rating will be required based on the actual environmental conditions.

Device on 40 mm x 40 mm x 1.5 mm epoxy PCB FR4 with 6 cm 2 (one layer, 70 μ m thick) copper area for drain connection. PCB is vertical in still air.

³⁾ See Diagram 3 for more detailed information

⁴⁾ See Diagram 13 for more detailed information

⁵⁾ The negative rating is for low duty cycle pulse occurrence. No continuous rating is implied



2 Thermal characteristics

Table 3 Thermal characteristics

Parameter	Symbol	Values			Unit	Nieto/Tost Condition
raiametei	Syllibot	Min.	Тур.	Мах.	Offic	Note/ Test Condition
Thermal resistance, junction - case, bottom	R_{thJC}	-	0.8	1.3	K/W	-
Thermal resistance, junction - case, top	R_{thJC}	-	-	20	K/W	-
Device on PCB, 6 cm ² cooling area ⁶⁾	R_{thJA}	-	-	50	K/W	-

Device on 40 mm x 40 mm x 1.5 mm epoxy PCB FR4 with 6 cm 2 (one layer, 70 μ m thick) copper area for drain connection. PCB is vertical in still air.



3 Electrical characteristics

unless otherwise specified

Table 4 Static characteristics

Parameter	Symbol		Values			Nato/Task Condition
raiailletei	Syllibot	Min.	Тур.	Мах.	Unit	Note/ Test Condition
Drain-source breakdown voltage	$V_{(BR)DSS}$	40	-	-	V	V_{GS} =0 V, I_D =1 mA
Gate threshold voltage	$V_{\rm GS(th)}$	1.2	-	2	V	$V_{\rm DS} = V_{\rm GS}, I_{\rm D} = 250 \mu{\rm A}$
Zero gate voltage drain current	I _{DSS}	-	0.1 10	1 100	μΑ	V_{DS} =40 V, V_{GS} =0 V, T_j =25 °C V_{DS} =40 V, V_{GS} =0 V, T_j =125 °C
Gate-source leakage current	I_{GSS}	-	10	100	nA	V _{GS} =20 V, V _{DS} =0 V
Drain-source on-state resistance	$R_{\mathrm{DS(on)}}$	-	1.5 1.1	1.9 1.4	mΩ	$V_{\rm GS}$ =4.5 V, $I_{\rm D}$ =50 A $V_{\rm GS}$ =10 V, $I_{\rm D}$ =50 A
Gate resistance ⁷⁾	R_{G}	0.45	0.9	1.8	Ω	-
Transconductance	g_{fs}	120	230	-	S	$ V_{\rm DS} > 2 I_{\rm D} R_{\rm DS(on)max}, I_{\rm D} = 50 \text{ A}$

⁷⁾ Defined by design. Not subject to production test

Table 5 Dynamic characteristics 8)

Darameter	Symbol	Values			Linit	Note / Test Condition
Parameter	Symbol	Min. Typ. Max.		Мах.	Unit	Note/ Test Condition
Input capacitance	C _{iss}	-	4300	6020	pF	V _{GS} =0 V, V _{DS} =20 V, <i>f</i> =1 MHz
Output capacitance	C _{oss}	-	1200	1680	pF	V _{GS} =0 V, V _{DS} =20 V, <i>f</i> =1 MHz
Reverse transfer capacitance	C _{rss}	-	100	200	pF	$V_{\rm GS}$ =0 V, $V_{\rm DS}$ =20 V, f =1 MHz
Turn-on delay time	$t_{\sf d(on)}$	_	8	-	ns	$V_{\rm DD}$ =20 V, $V_{\rm GS}$ =10 V, $I_{\rm D}$ =50 A, $R_{\rm G,ext}$, ext=1.6 Ω
Rise time	t _r	-	9	-	ns	$V_{\rm DD}$ =20 V, $V_{\rm GS}$ =10 V, $I_{\rm D}$ =50 A, $R_{\rm G,ext}$, ext=1.6 Ω
Turn-off delay time	$t_{\sf d(off)}$	-	35	-	ns	$V_{\rm DD}$ =20 V, $V_{\rm GS}$ =10 V, $I_{\rm D}$ =50 A, $R_{\rm G,ext}$, ext=1.6 Ω
Fall time	t_{f}	_	7	-	ns	$V_{\rm DD}$ =20 V, $V_{\rm GS}$ =10 V, $I_{\rm D}$ =50 A, $R_{\rm G,ext}$, ext=1.6 Ω

⁸⁾ Defined by design. Not subject to production test

Table 6 Gate charge characteristics 9)

Parameter	Symbol	Values			Unit	Note/ Test Condition
rameter Symbol	Syllibot	Min.	Тур.	Мах.	Unit	Note/ Test Condition
Gate to source charge	$Q_{ m gs}$	-	11	-	nC	$V_{\rm DD}$ =20 V, $I_{\rm D}$ =50 A, $V_{\rm GS}$ =0 to 10 V
Gate charge at threshold	$Q_{\mathrm{g(th)}}$	-	6.9	-	nC	$V_{\rm DD}$ =20 V, $I_{\rm D}$ =50 A, $V_{\rm GS}$ =0 to 10 V
Gate to drain charge	$Q_{ m gd}$	-	9.8	14	nC	$V_{\rm DD}$ =20 V, $I_{\rm D}$ =50 A, $V_{\rm GS}$ =0 to 10 V



Table 6 Gate charge characteristics 9)

Parameter	Symbol	Values			Linit	Note / Test Condition
	Symbol	Min.	Тур.	Мах.	Unit	Note/ Test Condition
Switching charge	Q_{sw}	-	14	-	nC	$V_{\rm DD}$ =20 V, $I_{\rm D}$ =50 A, $V_{\rm GS}$ =0 to 10 V
Gate charge total	$Q_{ m g}$	-	61	85	nC	$V_{\rm DD}$ =20 V, $I_{\rm D}$ =50 A, $V_{\rm GS}$ =0 to 10 V
Gate plateau voltage	$V_{ m plateau}$	-	2.5	-	V	$V_{\rm DD}$ =20 V, $I_{\rm D}$ =50 A, $V_{\rm GS}$ =0 to 10 V
Gate charge total	$Q_{ m g}$	-	31	44	nC	$V_{\rm DD}$ =20 V, $I_{\rm D}$ =50 A, $V_{\rm GS}$ =0 to 4.5 V
Gate charge total, sync. FET	$Q_{g(sync)}$	-	24	-	nC	$V_{\rm DS}$ =0.1 V, $V_{\rm GS}$ =0 to 4.5 V
Output charge	Q _{oss}	-	54	76	nC	V _{DD} =20 V, V _{GS} =0 V

⁹⁾ See "Gate charge waveforms" for parameter definition. Defined by design. Not subject to production test

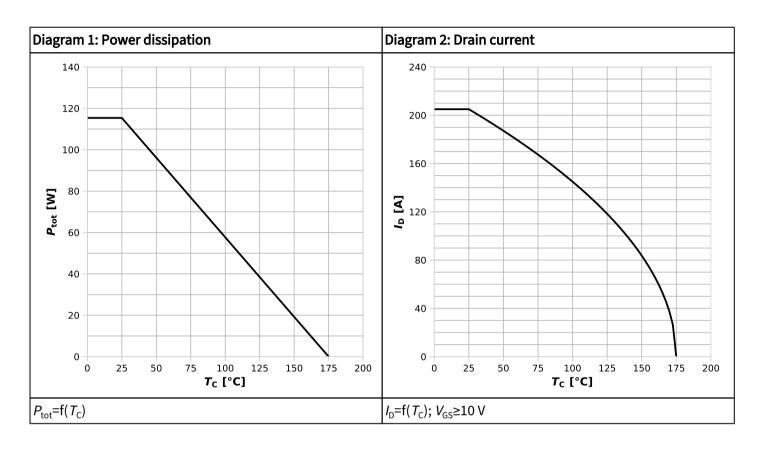
Table 7 Reverse diode

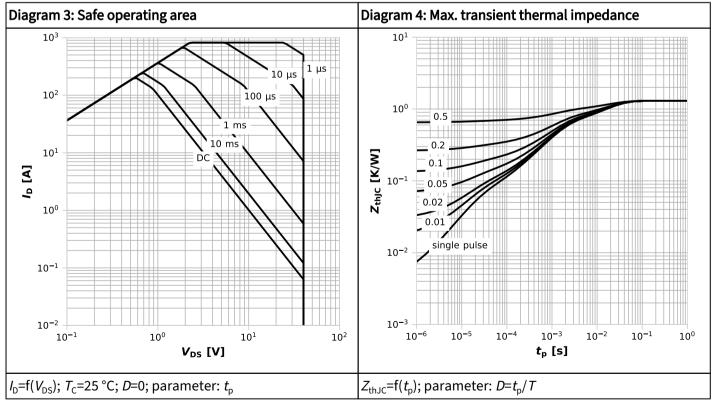
Darameter	Symbol	Values			l lmit	Note / Took Con dition
Parameter	Symbol	Min.	Тур.	Мах.	Unit	Note/ Test Condition
Diode continuous forward current	Is	-	-	115	А	T _C =25 °C
Diode pulse current	I _{S,pulse}	-	-	820	А	T _C =25 °C
Diode forward voltage	$V_{\rm SD}$	-	0.82	1	V	$V_{\rm GS}$ =0 V, $I_{\rm F}$ =50 A, $T_{\rm j}$ =25 °C
Reverse recovery time ¹⁰⁾	t _{rr}	-	32	64	ns	V _R =20 V, I _F =50A, d <i>i</i> _F /d <i>t</i> =400 A/μs
Reverse recovery charge ¹⁰⁾	$Q_{\rm rr}$	-	44	-	nC	$V_{\rm R}$ =20 V, $I_{\rm F}$ =50A, d $i_{\rm F}$ /d t =400 A/ μ s

 $^{^{10)}}$ Defined by design. Not subject to production test

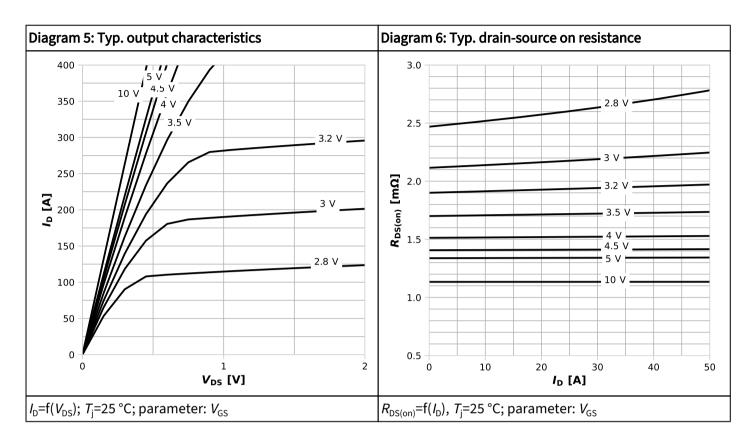


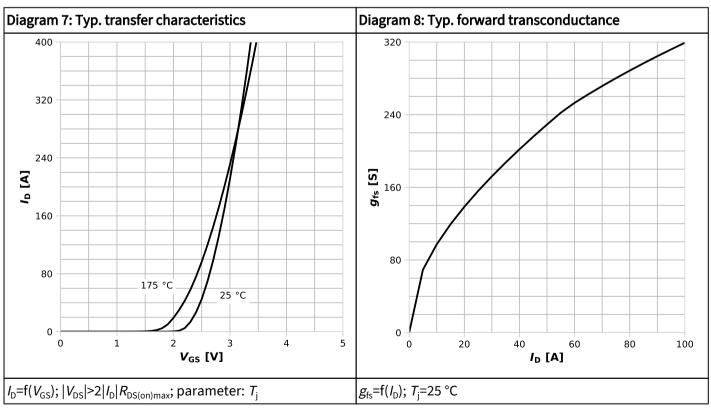
4 Electrical characteristics diagrams



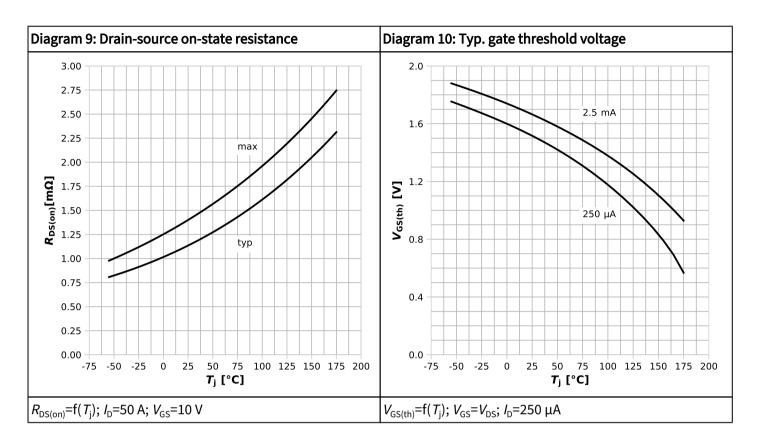


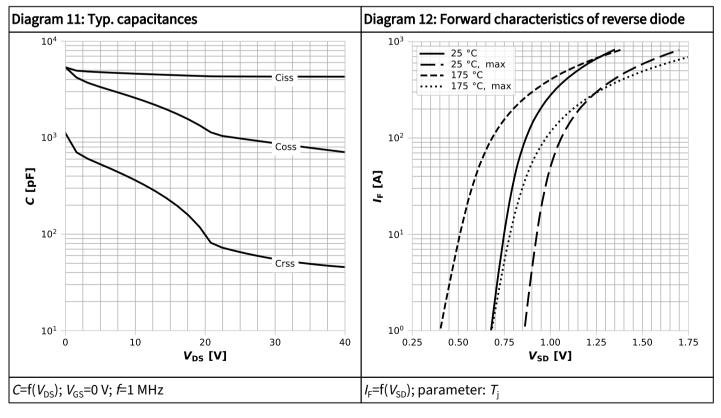




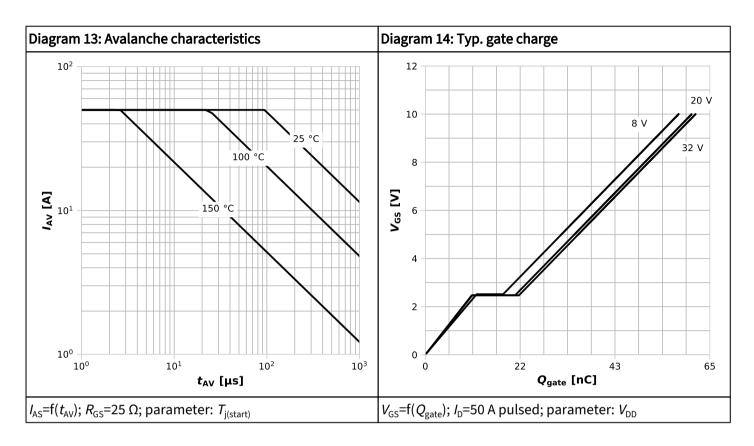


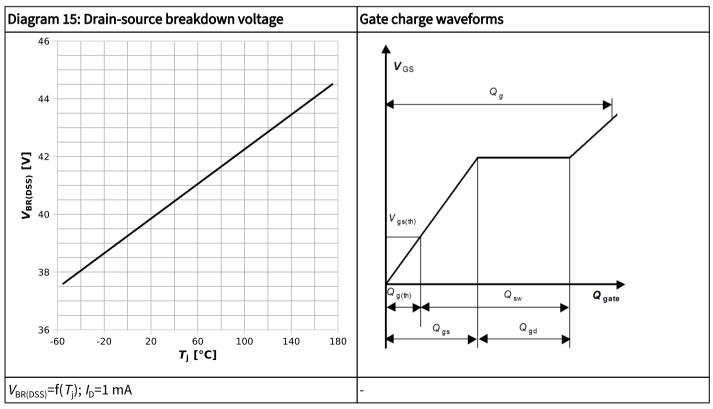














5 Package Outlines

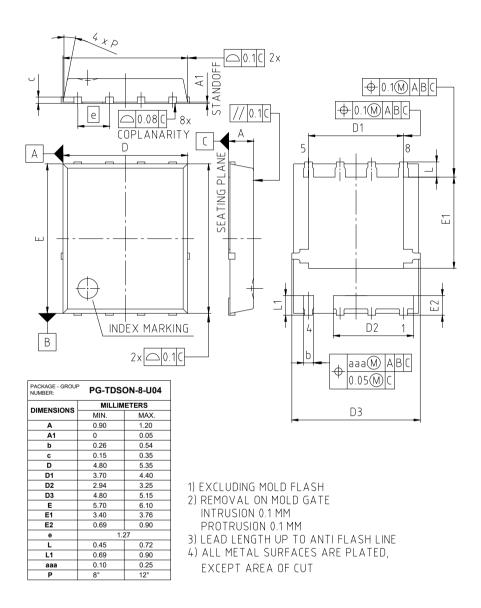


Figure 1 Outline PG-TDSON-8, dimensions in mm



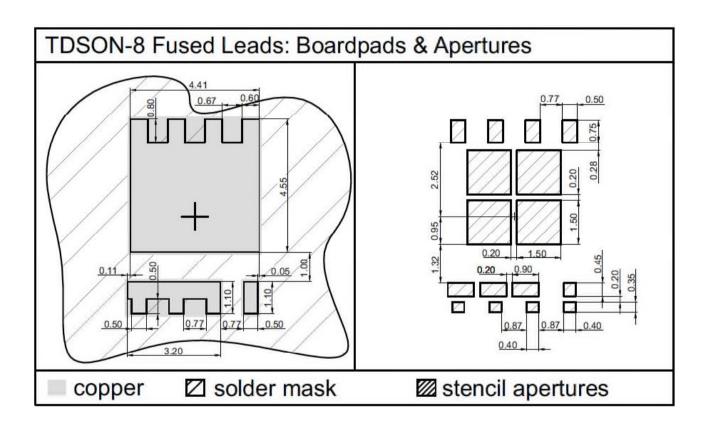


Figure 2 Outline PG-TDSON-8, dimensions in mm



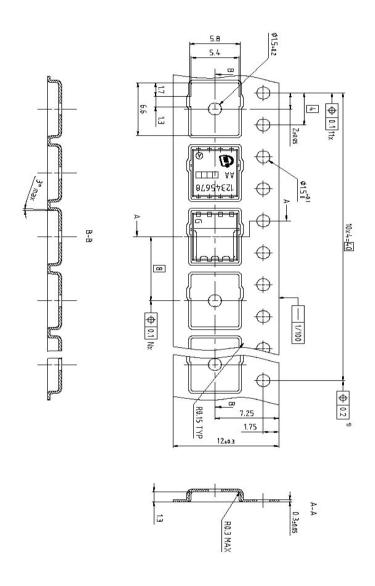


Figure 3 Outline PG-TDSON-8, dimensions in mm



Revision History

BSC014N04LS

Revision 2024-06-11, Rev. 2.9

Previous Revision

Revision	Date	Subjects (major changes since last revision)
2.0	2012-10-11	Release of final version
2.1	2012-10-12	New diagram titles.
2.2	2013-02-27	Rev. 2.1
2.4	2016-05-04	Update footnotes and insert max values
2.5	2017-03-27	Update Qrr
2.6	2020-02-07	Update package drawings
2.7	2020-05-15	Update current rating
2.8	2023-04-20	Update package outline drawings
2.9	2024-06-11	Upgrade Operating and storage temperature max to 175°C. Update drawings in section 5 Package Outlines. Production validation added on page1.Updated foot notes.

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